UNISONIC TECHNOLOGIES CO., LTD

1N50-SE **Power MOSFET**

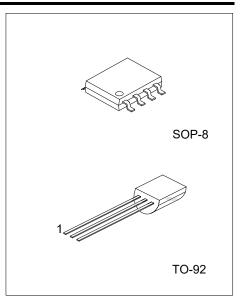
1.0A, 500V N-CHANNEL **POWER MOSFET**

DESCRIPTION

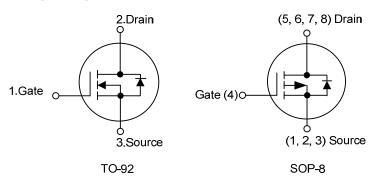
The UTC 1N50-SE is a high voltage MOSFET and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristics. This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient AC to DC converters and bridge circuits.

FEATURES

- * $R_{DS(ON)} \le 10.6 \Omega$ @ $V_{GS}=10V$, $I_D=0.5A$
- * Fast switching capability
- * Avalanche energy specified
- * Improved dv/dt capability, high ruggedness



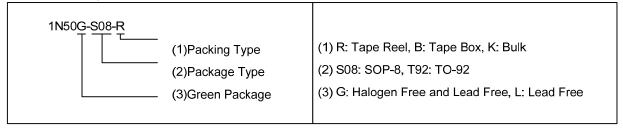
SYMBOL



ORDERING INFORMATION

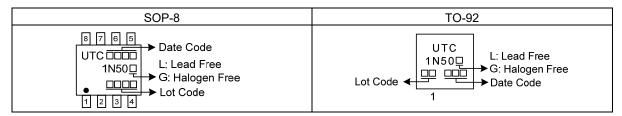
Ordering Number		Deelsene	Pin Assignment							Daakina	
Lead Free	Halogen Free	Package	1	2	3	4	5	6	7	8	Packing
1N50L-S08-R	1N50G-S08-R	SOP-8	S	ഗ	S	G	D	ם	ם	О	Tape Reel
1N50L-T92-B	1N50G-T92-B	TO-92	G	D	S	-	-	•	•	-	Tape Box
1N50L-T92-K	1N50G-T92-K	TO-92	G	D	S	-	-	-	-	-	Bulk

Pin Assignment: G: Gate D: Drain S: Source



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MARKING



1N50-SE Power MOSFET

■ ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	500	V
Gate-Source Voltage		V_{GSS}	±30	V
Drain Current	Continuous	I _D	1.0	Α
	Pulsed (Note 2)	I_{DM}	2.0	Α
Peak Diode Recovery dv/dt (Note 4)		dv/dt	1.4	V/ns
Power Dissipation	SOP-8		1.8	W
	TO-92	P_D	1.2	W
Junction Temperature		TJ	+150	°C
Storage Temperature		T _{STG}	-55 ~ + 150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. $I_{SD} \le 1.0 A$, di/dt $\le 200 A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25 ^{\circ}C$

■ THERMAL DATA

PARAMETER		SYMBOL	RATINGS	UNIT	
Junction to Ambient	SOP-8	0	90	°C/W	
	TO-92	θ_{JA}	160	°C/W	
Junction to Case	SOP-8	0	69.4	°C/W	
	TO-92	$\theta_{ m JC}$	104	°C/W	

Note: Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

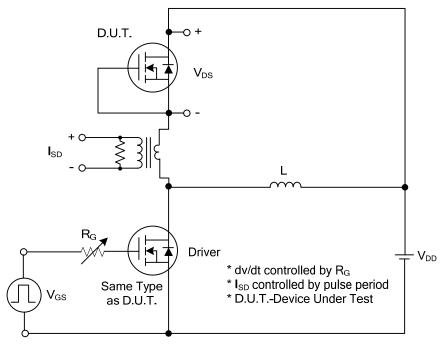
■ ELECTRICAL CHARACTERISTICS (T_J =25°C, unless otherwise specified)

				1					
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
OFF CHARACTERISTICS									
Drain-Source Breakdown Voltage		BV _{DSS}	V_{GS} =0V, I_D =250 μ A	500			V		
Drain-Source Leakage Current		I _{DSS}	V _{DS} =500V, V _{GS} =0V			10	μΑ		
Gate-Source Leakage Current	Forward	1	V_{GS} =30V, V_{DS} =0V			100	nA		
	Reverse	I_{GSS}	V_{GS} =-30V, V_{DS} =0V			-100	nA		
ON CHARACTERISTICS									
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$	2.0		4.0	V		
Static Drain-Source On-State Resistance		R _{DS(ON)}	V_{GS} =10V, I_{D} =0.5A			10.6	Ω		
DYNAMIC CHARACTERISTICS	3	_		-	ā.				
Input Capacitance	Input Capacitance				84		pF		
Output Capacitance		Coss	V _{DS} =25V, V _{GS} =0V, f=1MHz		15		pF		
Reverse Transfer Capacitance		C _{RSS}			2.2		pF		
SWITCHING CHARACTERISTIC	cs								
Total Gate Charge (Note 1)		Q_{G}	V -400V V -40V		7.3		nC		
Gate to Source Charge		Q_GS	V _{DS} =400V, V _{GS} =10V, I _D =1.0A, (Note 1, 2)		2.5		nC		
Gate to Drain Charge		Q_{GD}	1D-1.0A, (Note 1, 2)		0.7		nC		
Turn-ON Delay Time (Note 1)		t _{D (ON)}			3.8		ns		
Rise Time		t _R	V _{DD} =100V, V _{GS} =10V,		14.2		ns		
Turn-OFF Delay Time		t _{D (OFF)}	I_D =1.0A, R_G =25 Ω (Note 1, 2)		11		ns		
Fall-Time		t _F			33.7		ns		
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS									
Maximum Body-Diode Continuous Current		Is				1.0	Α		
Maximum Body-Diode Pulsed Current (Note 1)		I _{SM}				2.0	Α		
Drain-Source Diode Forward Voltage (Note 1)		V_{SD}	I _S =1.0A, V _{GS} =0V			1.4	V		
Body Diode Reverse Recovery Time		t _{rr}	I _S =1.0A, V _{GS} =0V		113		ns		
Body Diode Reverse Recovery (Q _{rr}	dI _F /dt=100A/μs		0.7		μC			
			-						

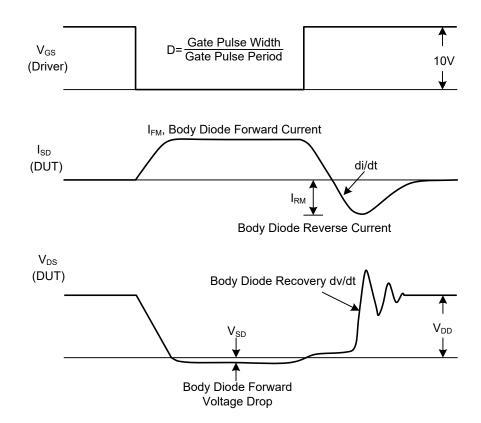
Notes: 1. Pulse Test: Pulse Width≤300µs, Duty Cycle≤2%

^{2.} Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS



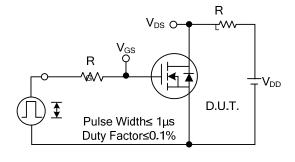
Peak Diode Recovery dv/dt Test Circuit



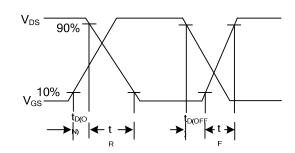
Peak Diode Recovery dv/dt Waveforms

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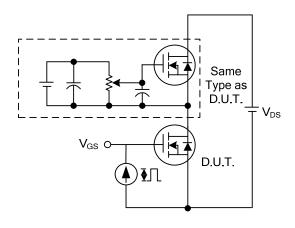
■ TEST CIRCUITS AND WAVEFORMS



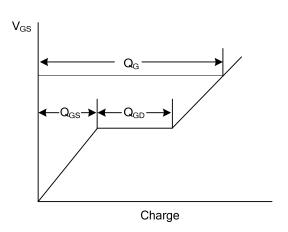
Switching Test Circuit



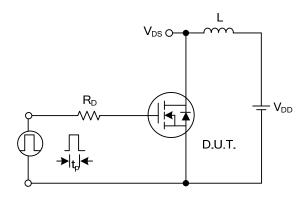
Switching Waveforms



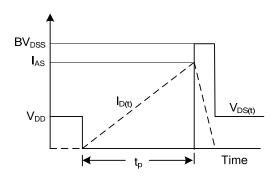
Gate Charge Test Circuit



Gate Charge Waveform

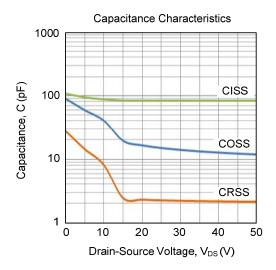


Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

■ TYPICAL CHARACTERISTICS



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